

IN THE SPECIFICATION

Please replace the title at page 1, line 2, with the following title:

METHOD FOR SIMULATING VARIATIONS IN DEVICE PARAMETERS
RESULTING FROM SEMICONDUCTOR MANUFACTURE

Please amend the paragraph at page 6, lines 3-8, as follows:

Conventionally, a device parameter set at each corner point has been determined by a method as shown in Fig. 11. First, initial values of a device parameter set at each corner point ~~varying depending on variations~~ are provided to a simulator as in step S102. The initial values used herein may include recorded values of the variations specified based on past data in a manufacturing line, values of measurement obtained by new sampling, and the like.